

Notice of References Cited	Application/Control No. 10/534,488	Applicant(s)/Patent Under Reexamination INADA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,099,287 A	08-2000	Higashida et al.	425/190
*	B	US-6,139,307 A	10-2000	Plourde et al.	425/192R
*	C	US-6,164,952 A	12-2000	Asai, Ikuo	425/542
*	D	US-6,238,197 B1	05-2001	Van Hout et al.	425/168
*	E	US-6,322,350 B1	11-2001	Voets et al.	425/548
*	F	US-6,514,437 B1	02-2003	Higashida et al.	264/1.33
*	G	US-6,558,152 B2	05-2003	Yasuda et al.	425/552
*	H	US-6,761,553 B2	07-2004	Kurisu et al.	425/182
*	I	US-7,044,726 B2	05-2006	Koyama et al.	425/192R
*	J	US-7,128,562 B2	10-2006	Doi et al.	425/548
*	K	US-7,229,275 B2	06-2007	Nakano et al.	425/553
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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